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Xi Chen; Hsieh, H.; Balarin, F.; Watanabe, Y.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 23 , Issue: 8 , Aug. 2004
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[\[Abstract\]](#) [\[PDF Full-Text \(336KB\)\]](#) IEEE JNL

2 Techniques for the optimum synthesis of multipole control systems with random processes as inputs

Hsieh, H.; Leondes, C.;

Automatic Control, IRE Transactions on , Volume: 4 , Issue: 3 , Dec 1959
Pages:212 - 231

[\[Abstract\]](#) [\[PDF Full-Text \(912KB\)\]](#) IEEE JNL

3 On the optimum synthesis of multipole control systems in the weiner sense

Hsieh, H.; Leondes, C.;

Automatic Control, IRE Transactions on , Volume: 4 , Issue: 2 , Nov 1959
Pages:16 - 29

[\[Abstract\]](#) [\[PDF Full-Text \(896KB\)\]](#) IEEE JNL

4 On the optimum synthesis of sampled data multipole filters with random and nonrandom inputs

Hsieh, H.; Leondes, C.;

Automatic Control, IRE Transactions on , Volume: 5 , Issue: 3 , Aug 1960
Pages:193 - 208

[\[Abstract\]](#) [\[PDF Full-Text \(752KB\)\]](#) IEEE JNL

5 Analysis of grating-coupled emission in lead-tin telluride diode lasers

Hsieh, H.; Fonstad, C.;

Quantum Electronics, IEEE Journal of , Volume: 13 , Issue: 8 , Aug 1977
Pages:681 - 686

[\[Abstract\]](#) [\[PDF Full-Text \(1880KB\)\]](#) IEEE JNL

6 Metropolis: an integrated electronic system design environment

Balarin, F.; Watanabe, Y.; Hsieh, H.; Lavagno, L.; Passerone, C.; Sangiovanni-Vincentelli, A.;

Computer ,Volume: 36 , Issue: 4 , April 2003

Pages:45 - 52

[\[Abstract\]](#) [\[PDF Full-Text \(272KB\)\]](#) IEEE JNL

7 Synchronous approach to the functional equivalence of embedded system implementations

Hsieh, H.; Balarin, F.; Lavagno, L.; Sangiovanni-Vincentelli, A.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on ,Volume: 20 , Issue: 8 , Aug. 2001

Pages:1016 - 1033

[\[Abstract\]](#) [\[PDF Full-Text \(316KB\)\]](#) IEEE JNL

8 Synthesis of software programs for embedded control applications

Balarin, F.; Chiodo, M.; Giusto, P.; Hsieh, H.; Jurecska, A.; Lavagno, L.;

Sangiovanni-Vincentelli, A.; Sentovich, E.M.; Suzuki, K.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on ,Volume: 18 , Issue: 6 , June 1999

Pages:834 - 849

[\[Abstract\]](#) [\[PDF Full-Text \(240KB\)\]](#) IEEE JNL

9 Prediction intervals for Weibull observations, based on early-failure data

Hsieh, H.K.;

Reliability, IEEE Transactions on ,Volume: 45 , Issue: 4 , Dec. 1996

Pages:666 - 670

[\[Abstract\]](#) [\[PDF Full-Text \(364KB\)\]](#) IEEE JNL

10 Effect of surface recombination velocity on the threshold current and differential quantum efficiency of the surface-emitting laser diode

Ogura, M.; Hsieh, H.C.;

Quantum Electronics, IEEE Journal of ,Volume: 32 , Issue: 4 , April 1996

Pages:597 - 606

[\[Abstract\]](#) [\[PDF Full-Text \(884KB\)\]](#) IEEE JNL

11 Average type-II censoring times for the 2-parameter Weibull distribution

Hsieh, H.K.;

Reliability, IEEE Transactions on ,Volume: 43 , Issue: 1 , March 1994

Pages:91 - 96

[\[Abstract\]](#) [\[PDF Full-Text \(392KB\)\]](#) IEEE JNL

12 Hardware-software codesign of embedded systems

Chiodo, M.; Giusto, P.; Jurecska, A.; Hsieh, H.C.; Sangiovanni-Vincentelli, A.;

Lavagno, L.;

Micro, IEEE ,Volume: 14 , Issue: 4 , Aug. 1994

Pages:26 - 36

[\[Abstract\]](#) [\[PDF Full-Text \(2192KB\)\]](#) IEEE JNL

13 Power partition and emitter size optimization for bipolar ECL circuit*Hsieh, H.Y.; Chin, K.; Chuang, C.-T.;*

Solid-State Circuits, IEEE Journal of , Volume: 28 , Issue: 5 , May 1993

Pages:548 - 552

[\[Abstract\]](#) [\[PDF Full-Text \(448KB\)\]](#) [IEEE JNL](#)**14 Asymmetry in the optical output power characteristics of a short-external-cavity laser diode***Kim, J.-Y.; Hsieh, H.C.;*

Photonics Technology Letters, IEEE , Volume: 4 , Issue: 6 , June 1992

Pages:537 - 539

[\[Abstract\]](#) [\[PDF Full-Text \(256KB\)\]](#) [IEEE JNL](#)**15 An open-resonator model for the analysis of a short external-cavity laser diode and its application to the optical disk head***Kim, J.-Y.; Hsieh, H.C.;*

Lightwave Technology, Journal of , Volume: 10 , Issue: 4 , April 1992

Pages:439 - 447

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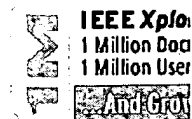
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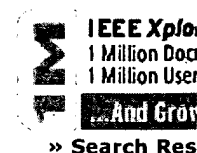
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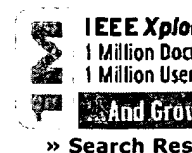
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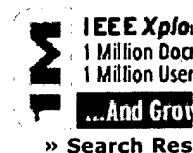
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